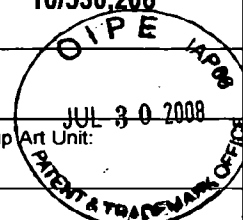


(Use several sheets if necessary)

Application No.: **10/530.206**

Filing Date:
April 4, 2005

Group Art Unit:



U.S. PATENT DOCUMENTS

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FOREIGN PATENT DOCUMENTS

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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

+		Karl Weiers et al., "Oxides and Hydroxides of Aluminum", Alcoa Laboratories, pages 64-66, D
*		Frank Hanglein, "Oxidschichtdicken auf Al-Pigmenten", nano-Analyses GmbH, October 2, 2007, pages 1-6, D2
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EXAMINER:

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DATE CONSIDERED

09/20/2008

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

* Abstract provided for the Examiner's convenience

* Non-English documents without translation.

+ Undated documents.

INFORMATION DISCLOSURE CITATION IN AN APPLICATION (Use several sheets if necessary)		Attorney Docket No.: 0512-1269	Application No.: 10/530,206
		Applicant: Etienne DUGUET et al.	
		Filing Date: April 4, 2005	Group Art Unit:
+		Al layer thickness", nanoAnalytics, D11	
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	/H.L./	G. Ertl, J. Kuppers, "Low energy electrons and surface chemistry", VCH Verlagsgesellschaft mbH, 1985, pages 54-56, D14	

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